

## DEVELOPMENT OF PEPPER-POT EMITTANCE MONITOR FOR

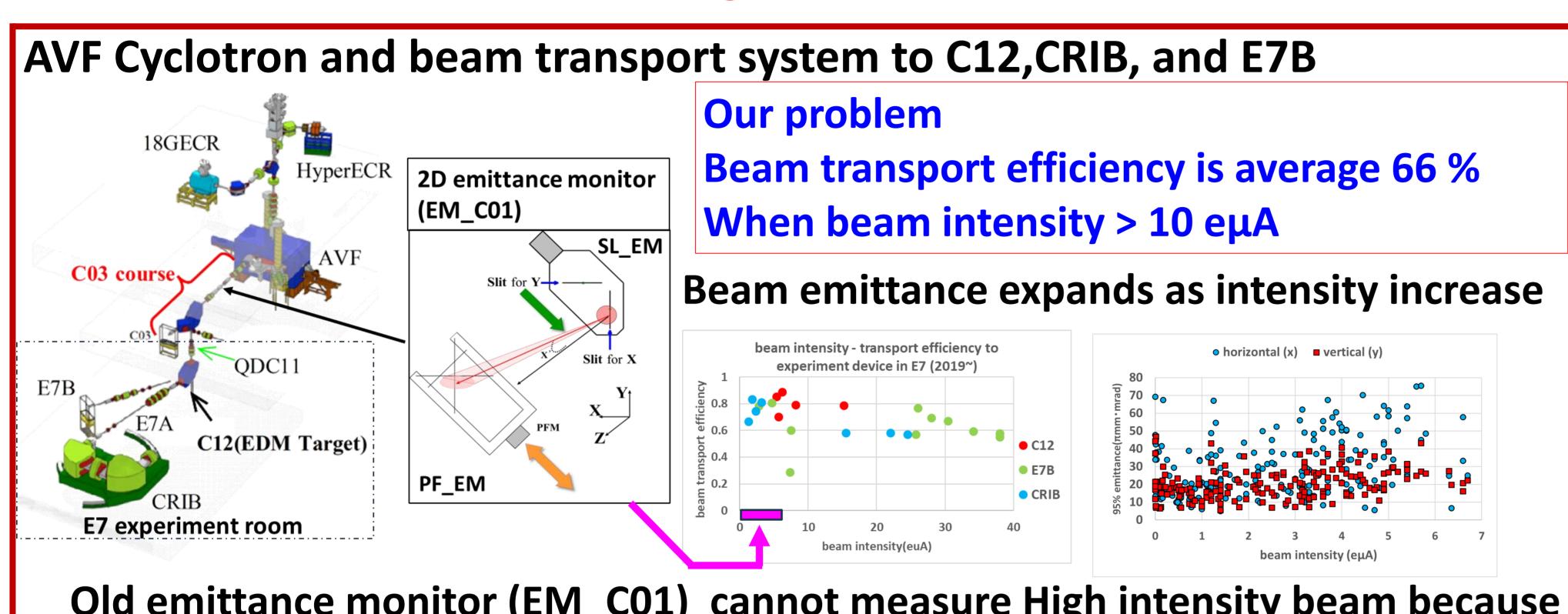


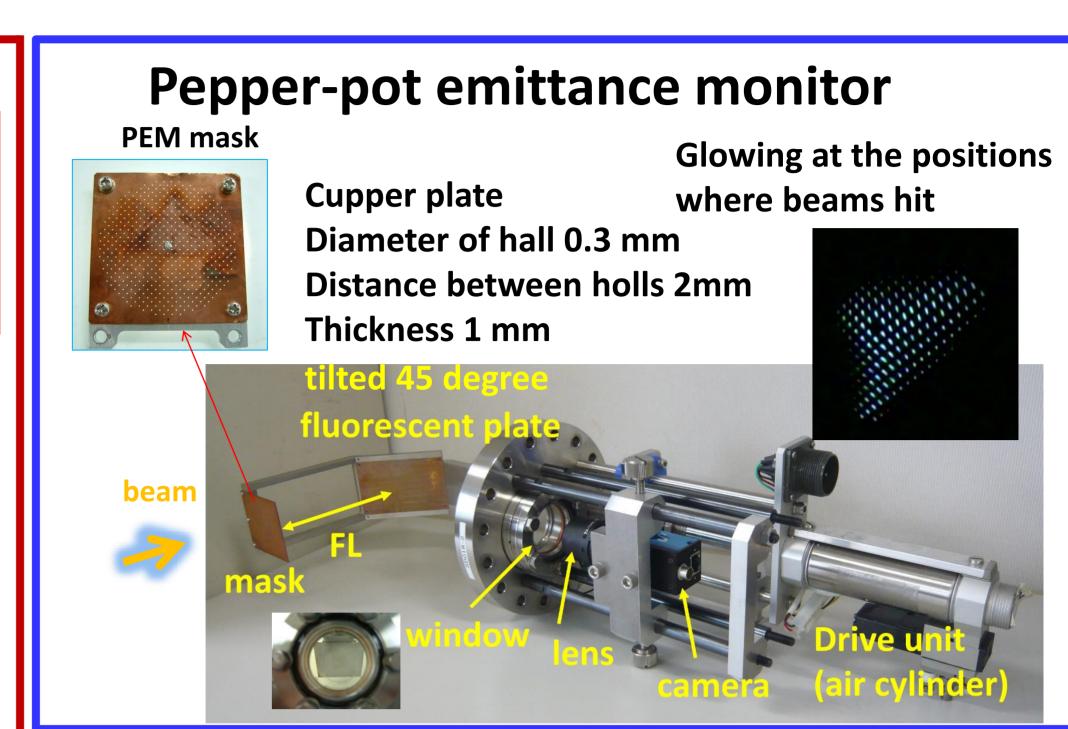
## HIGH-INTENSITY ION BEAM ACCELERATED BY RIKEN AVF CYCLOTRON

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At the Center for Nuclear Study of the University of Tokyo (CNS), the measurement of Electric Dipole Moment (EDM) of Francium (Fr) is underway with the world highest precision. Fr is generated by nuclear fusion reaction by irradiating the gold (Au) target of EDM experiment device (EDM target) with oxygen ion beam 1806+ of 7 MeV/u accelerated by RIKEN AVF Cyclotron.

Our goal is transporting beam of more than 18 eµA (400 W), without loss and converging beam to be 1 mm of SD of beam distribution on the EDM target.

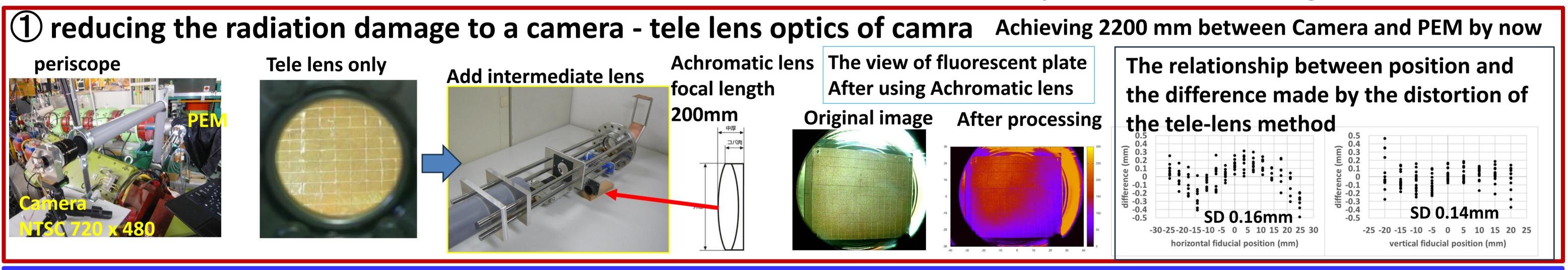




Old emittance monitor (EM\_C01) cannot measure High intensity beam because Cooling Ability < 130 W beam. has unsolved measurement error.

Developing Pepper-pot emittance monitor for high intensity beam We need more three additional development.

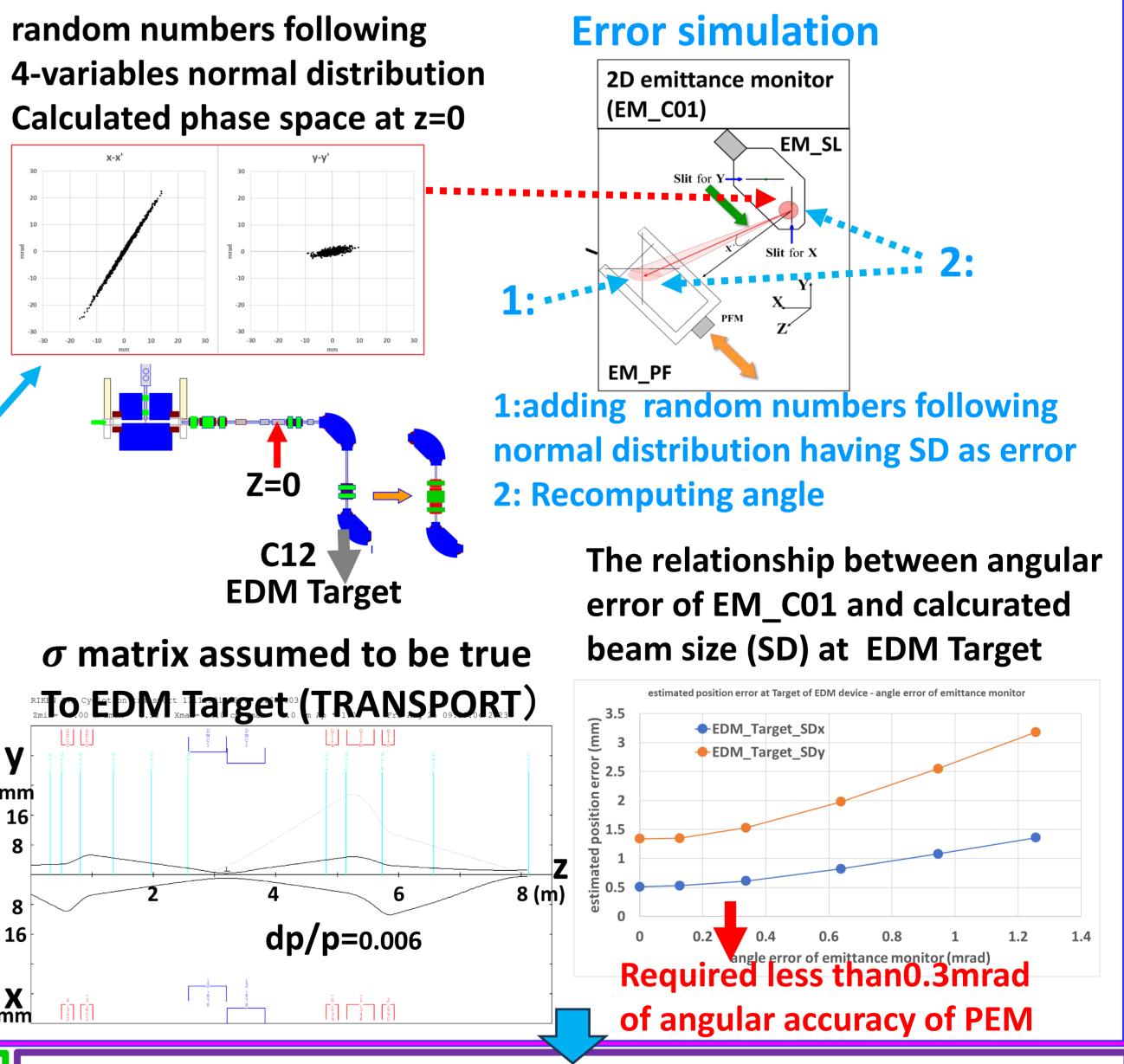
- 1) reducing the radiation damage to a camera
- 2 required angular accuracy for the accelerated beam
- (3) beam shutter system to avoid heating PEM due to beam





Schematic view of C03 beam line Equation of  $\sigma$  matrix.  $\sigma$ 11 known  $\langle \sigma_{11}(C02) \rangle$  $m_{12} m_{13} \setminus (\sigma_{11}(EM))$  $\sigma_{21}(C02) = \begin{bmatrix} m_{21} & m_{22} & m_{23} \end{bmatrix} \sigma_{21}(EM)$  $\sigma_{22}(C02)$  $\sigma_{11}(C03)$ <sup>19</sup>F<sup>7+</sup> 6.68MeV/u 5eμA  $\sigma_{21}(C03)$  $\sigma_{21}(C02)$  $I = I \cap$ Measured beam profile by PF EM  $\sigma_{22}(C03)$ Solution of equation(SDx of PF\_EM 8 mm) **SD 7.1mm 2.8mm** → not **80 %60**30 -30 1.69 Measured beam profile by PF\_C02  $\sigma$  matrix assumed to be true SD At EM\_C01 5.6mm 4.8mm PF\_C03 calculated using above  $\sigma$  matrix Measured beam profile by PF\_C03 similar **1.3mm 1.6mm** 

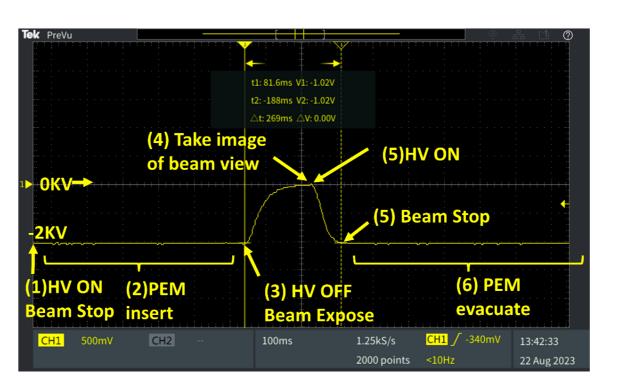
estimate the beam size including error at the EDM target due to the EM\_C01 measurement error.



(3) Beam shutter system to avoid heating PEM from beam No cooling — to shorten the measurement time

The beam stops by applying a high voltage to the electrode set in the beam line just behind an ion source and bending the beam sideways.

The measuring time reachs 0.27 seconds The diagram of the beam shutter control system HV power supply(C9619) -2kV, rising time 0.15 sec Serial DC-DC | 5VVcont Vcc IN 15V PC **HV ON HV OFF** HV out High voltage probe  $1 M\Omega$ (FLUKE 80K-40) Go Bending -2V 1:1000 straight beam oscilloscope



Dividing the measurement errors of PEM from the emittance assumed to be true by error simulation.

Our requirement for facility of beam test

- low beam emittance,
  - no correlation between x and y,
  - three BPMs in a beam line,

Micro Analysis Laboratory, Tandem accelerator (MALT), The University of Tokyo. The PEM installation with tele lens camera optics was complete. This beamline has two BPMs at 735 mm upstream and 2070 mm downstream from the PEM. Moreover, since the PEM becomes BPM with the average position error of 0.15 mm, we have three BPMs.